

## N-channel 650 V, 0.090 $\Omega$ typ., 22.5 A MDmesh™ M5 Power MOSFET in a PowerFLAT™ 8x8 HV package

Datasheet - production data

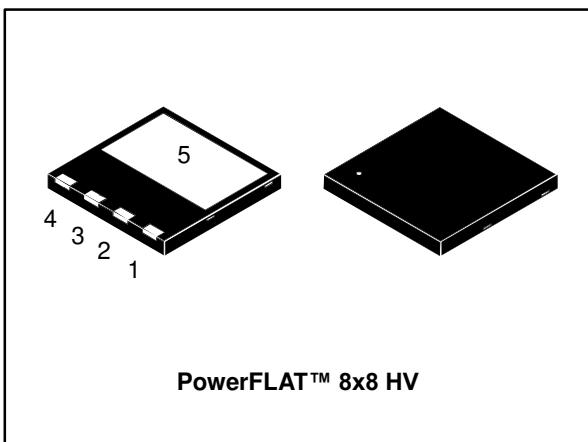
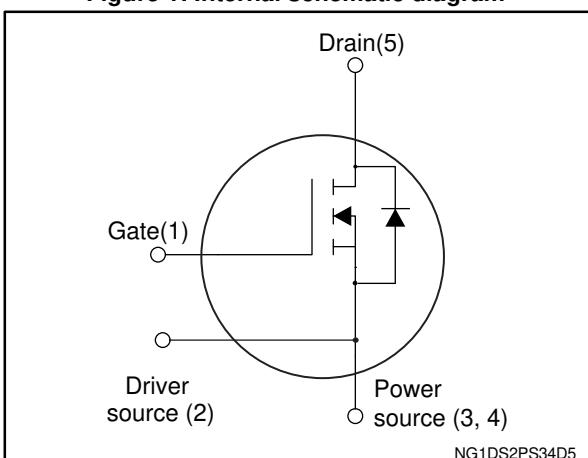


Figure 1: Internal schematic diagram



### Features

Order code	V <sub>DS</sub> @ T <sub>Jmax</sub>	R <sub>DS(on)</sub> max.	I <sub>D</sub>
STL38N65M5	710 V	0.105 $\Omega$	22.5 A

- Extremely low R<sub>DS(on)</sub>
- Low gate charge and input capacitance
- Excellent switching performance
- 100% avalanche tested

### Applications

- Switching applications

### Description

This device is an N-channel Power MOSFET based on the MDmesh™ M5 innovative vertical process technology combined with the well-known PowerMESH™ horizontal layout. The resulting product offers extremely low on-resistance, making it particularly suitable for applications requiring high power and superior efficiency.

Table 1: Device summary

Order code	Marking	Package	Packaging
STL38N65M5	38N65M5	PowerFLAT™ 8x8 HV	Tape and reel

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# 1 Electrical ratings

Table 2: Absolute maximum ratings

Symbol	Parameter	Value	Unit
$V_{DS}$	Drain-source voltage	650	V
$V_{GS}$	Gate-source voltage	$\pm 25$	V
$I_D^{(1)}$	Drain current (continuous) at $T_C = 25^\circ\text{C}$	22.5	A
$I_D^{(1)}$	Drain current (continuous) at $T_C = 100^\circ\text{C}$	16	A
$I_{DM}^{(1)(2)}$	Drain current (pulsed)	90	A
$I_D^{(3)}$	Drain current (continuous) at $T_{pcb} = 25^\circ\text{C}$	3.5	A
$I_D^{(3)}$	Drain current (continuous) at $T_{pcb} = 100^\circ\text{C}$	2.2	A
$P_{TOT}^{(3)}$	Total dissipation at $T_{pcb} = 25^\circ\text{C}$	2.8	W
$P_{TOT}^{(1)}$	Total dissipation at $T_C = 25^\circ\text{C}$	150	W
$I_{AR}$	Avalanche current, repetitive or notrepetitive (pulse width limited by $T_j$ max)	7	A
$E_{AS}$	Single pulse avalanche energy (starting $T_j = 25^\circ\text{C}$ , $I_D = I_{AR}$ , $V_{DD} = 50\text{ V}$ )	660	mJ
$dv/dt^{(4)}$	Peak diode recovery voltage slope	15	V/ns
$T_{stg}$	Storage temperature	- 55 to 150	$^\circ\text{C}$
$T_j$	Max. operating junction temperature	150	

**Notes:**(1)The value is rated according to  $R_{thj\text{-case}}$ .

(2)Pulse width limited by safe operating area.

(3)When mounted on FR-4 board of 1 inch<sup>2</sup>, 2oz Cu.(4) $I_{SD} \leq 22.5\text{ A}$ ,  $di/dt \leq 400\text{ A}/\mu\text{s}$ ;  $V_{DS(\text{peak})} < V_{(\text{BR})DSS}$ ,  $V_{DD} = 400\text{ V}$ .

Table 3: Thermal data

Symbol	Parameter	Value	Unit
$R_{thj\text{-case}}$	Thermal resistance junction-case max	0.83	$^\circ\text{C/W}$
$R_{thj\text{-pcb}}^{(1)}$	Thermal resistance junction-pcb max	45	$^\circ\text{C/W}$

**Notes:**(1)When mounted on FR-4 board of 1 inch<sup>2</sup>, 2oz Cu.

## 2 Electrical characteristics

$T_c = 25^\circ\text{C}$  unless otherwise specified

Table 4: On/off states

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$V_{(\text{BR})\text{DSS}}$	Drain-source breakdown voltage	$V_{GS} = 0 \text{ V}, I_D = 1 \text{ mA}$	650			V
$I_{\text{DS}}^{\text{SS}}$	Zero gate voltage Drain current	$V_{GS} = 0 \text{ V}, V_{DS} = 650 \text{ V}$			1	$\mu\text{A}$
		$V_{GS} = 0 \text{ V}, V_{DS} = 650 \text{ V}, T_c = 125^\circ\text{C}$			100	$\mu\text{A}$
$I_{GSS}$	Gate-body leakage current	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 25 \text{ V}$			$\pm 100$	nA
$V_{GS(\text{th})}$	Gate threshold voltage	$V_{DS} = V_{GS}, I_D = 250 \mu\text{A}$	3	4	5	V
$R_{DS(\text{on})}$	Static drain-source on-resistance	$V_{GS} = 10 \text{ V}, I_D = 12.5 \text{ A}$		0.090	0.105	$\Omega$

Table 5: Dynamic

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$C_{iss}$	Input capacitance	$V_{DS} = 100 \text{ V}, f = 1 \text{ MHz}, V_{GS} = 0 \text{ V}$	-	3000	-	pF
$C_{oss}$	Output capacitance		-	74	-	pF
$C_{rss}$	Reverse transfer capacitance		-	5.8	-	pF
$C_{o(er)}^{(1)}$	Equivalent output capacitance energy related	$V_{DS} = 0 \text{ to } 80\% V_{(\text{BR})\text{DSS}}, V_{GS} = 0 \text{ V}$	-	70	-	pF
$C_{o(tr)}^{(2)}$	Equivalent output capacitance time related		-	244	-	pF
$R_G$	Intrinsic gate resistance	$f = 1 \text{ MHz}$	-	2.4	-	$\Omega$
$Q_g$	Total gate charge	$V_{DD} = 520 \text{ V}, I_D = 15 \text{ A}, V_{GS} = 10 \text{ V}$ (see <a href="#">Figure 16: "Gate charge test circuit"</a> )	-	71	-	nC
$Q_{gs}$	Gate-source charge		-	18	-	nC
$Q_{gd}$	Gate-drain charge		-	30	-	nC

**Notes:**

<sup>(1)</sup> $C_{o(er)}$  is defined as a constant equivalent capacitance giving the same stored energy as  $C_{oss}$  when  $V_{DS}$  increases from 0 to 80%  $V_{DSS}$

<sup>(2)</sup> $C_{o(tr)}$  is defined as a constant equivalent capacitance giving the same charging time as  $C_{oss}$  when  $V_{DS}$  increases from 0 to 80%  $V_{DSS}$

**Table 6: Switching times**

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$t_{d(V)}$	Voltage delay time	$V_{DD} = 400 \text{ V}$ , $I_D = 20 \text{ A}$ $R_G = 4.7 \Omega$ , $V_{GS} = 10 \text{ V}$ (see <a href="#">Figure 17: "Test circuit for inductive load switching and diode recovery times"</a> and <a href="#">Figure 20: "Switching time waveform"</a> )	-	66	-	ns
$t_{r(V)}$	Voltage rise time		-	9	-	ns
$t_{f(i)}$	Crossing fall time		-	9	-	ns
$t_{C(off)}$	Crossing time		-	13	-	ns

**Table 7: Source drain diode**

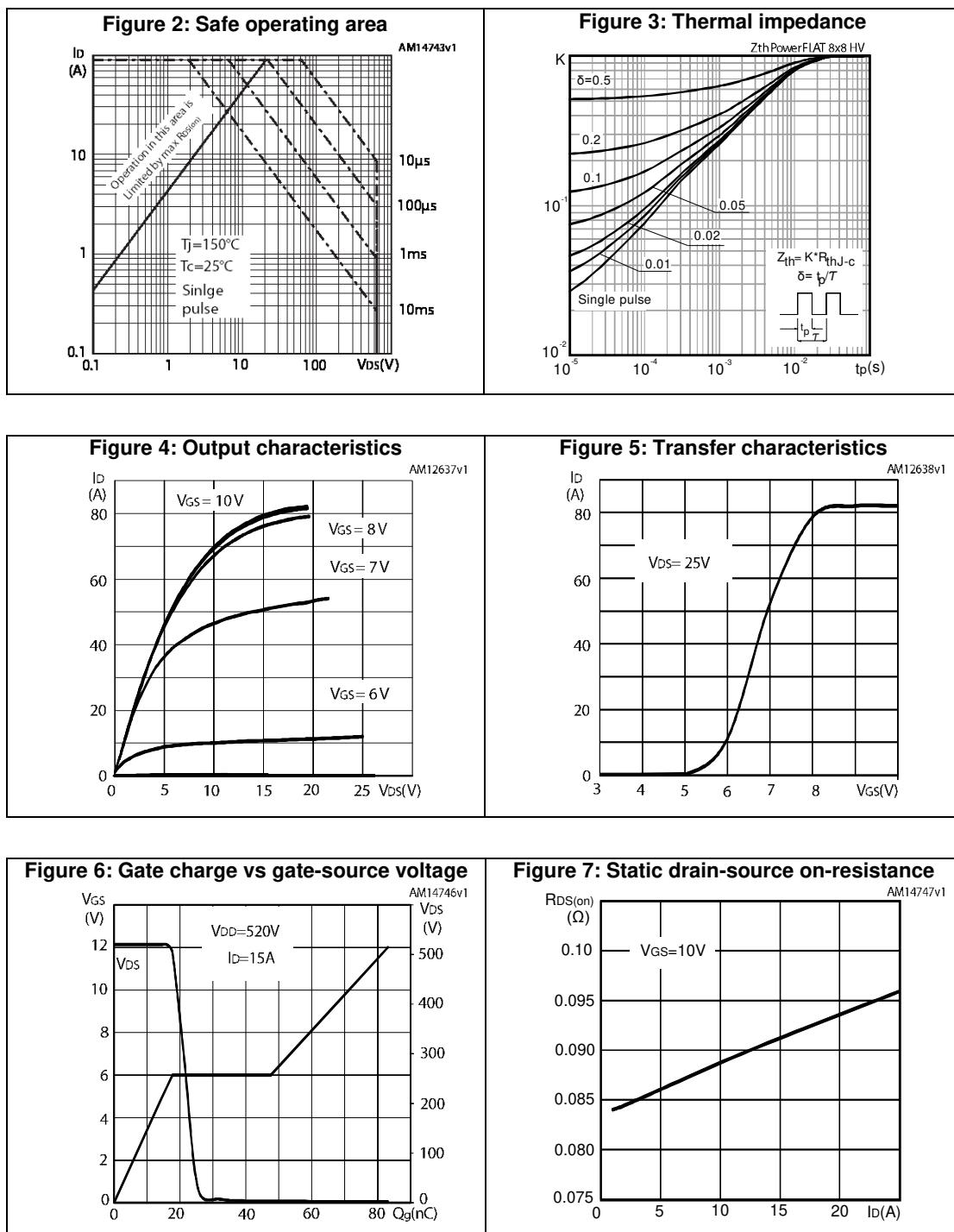
Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$I_{SD}^{(1)}$	Source-drain current		-		22.5	A
$I_{SDM}^{(1), (2)}$	Source-drain current (pulsed)		-		90	A
$V_{SD}^{(3)}$	Forward on voltage	$V_{GS} = 0 \text{ V}$ , $I_{SD} = 22.5 \text{ A}$	-		1.5	V
$t_{rr}$	Reverse recovery time	$I_{SD} = 22.5 \text{ A}$ , $dI/dt = 100 \text{ A}/\mu\text{s}$ , $V_{DD} = 100 \text{ V}$ (see <a href="#">Figure 17: "Test circuit for inductive load switching and diode recovery times"</a> )	-	354		ns
$Q_{rr}$	Reverse recovery charge		-	6		$\mu\text{C}$
$I_{RRM}$	Reverse recovery current		-	34		A
$t_{rr}$	Reverse recovery time	$I_{SD} = 22.5 \text{ A}$ , $dI/dt = 100 \text{ A}/\mu\text{s}$ , $V_{DD} = 100 \text{ V}$ , $T_j = 150^\circ\text{C}$ (see <a href="#">Figure 17: "Test circuit for inductive load switching and diode recovery times"</a> )	-	428		ns
$Q_{rr}$	Reverse recovery charge		-	8		$\mu\text{C}$
$I_{RRM}$	Reverse recovery current		-	38		A

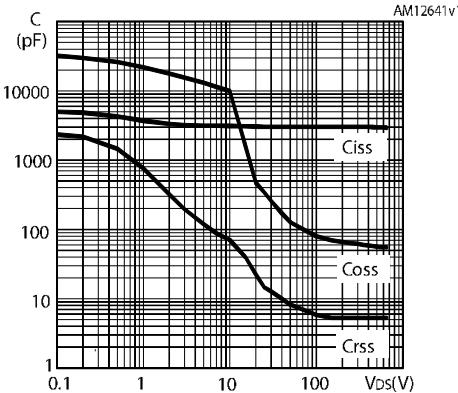
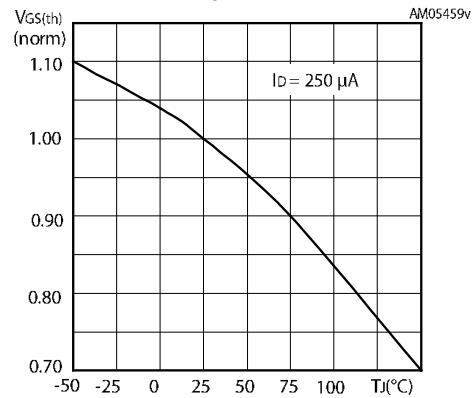
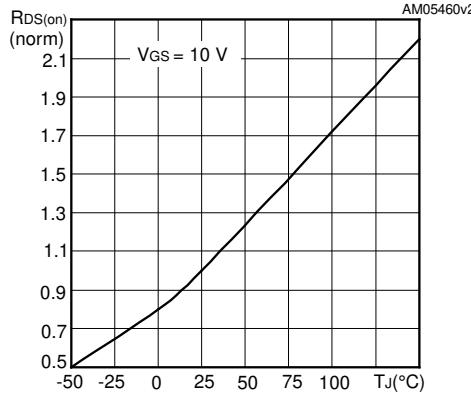
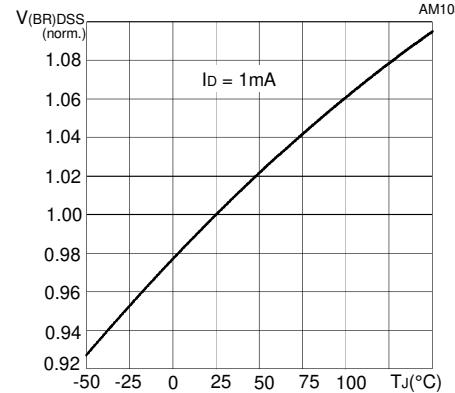
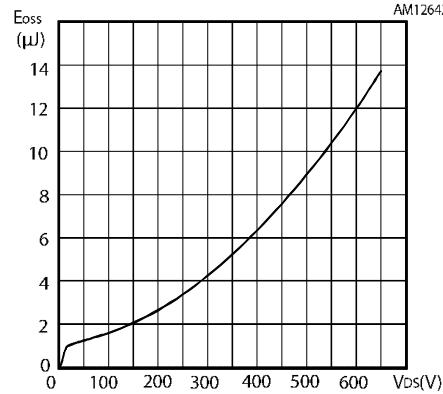
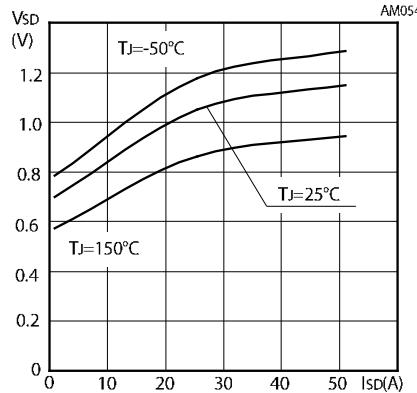
**Notes:**(1)The value is rated according to  $R_{thj-case}$  and limited by package.

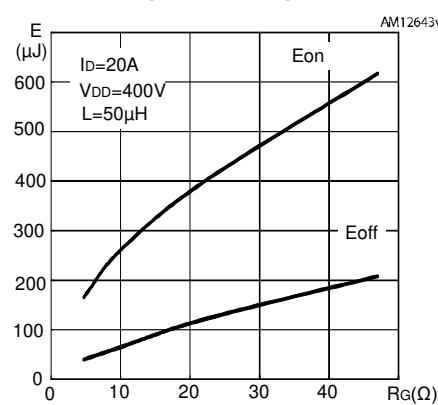
(2)Pulse width is limited by safe operating area

(3)Pulsed: pulse duration = 300  $\mu\text{s}$ , duty cycle 1.5%

## 2.1 Electrical characteristics (curves)



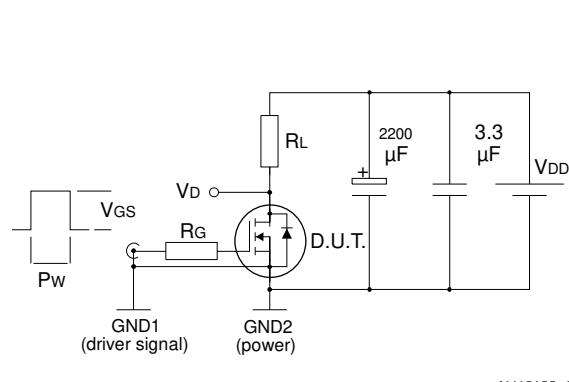
**Figure 8: Capacitance variations****Figure 9: Normalized gate threshold voltage vs temperature****Figure 10: Normalized on-resistance vs temperature****Figure 11: Normalized V(BR)DSS vs temperature****Figure 12: Output capacitance stored energy****Figure 13: Source-drain diode forward characteristics**

**Figure 14: Switching losses vs gate resistance**

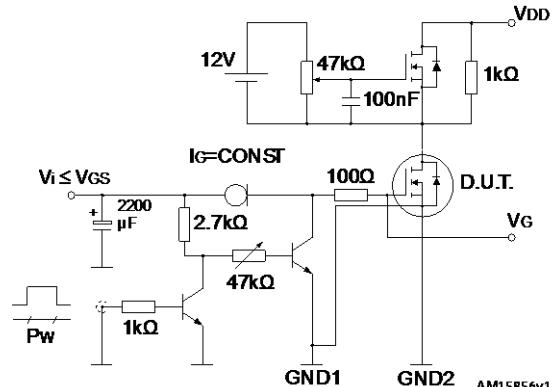
The previous figure  $E_{on}$  includes reverse recovery of a SiC diode.

## 3 Test circuits

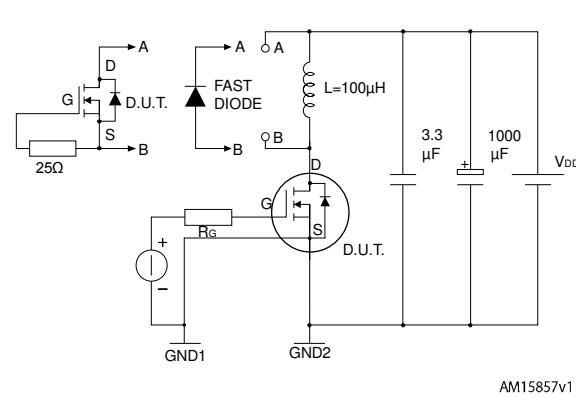
**Figure 15: Switching times test circuit for resistive load**



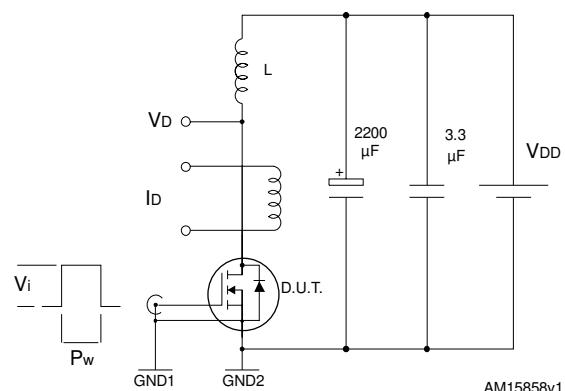
**Figure 16: Gate charge test circuit**



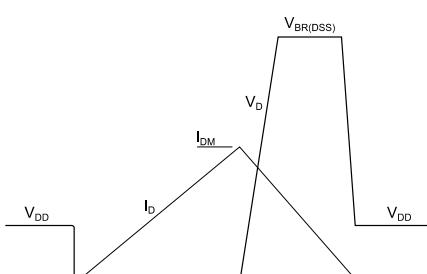
**Figure 17: Test circuit for inductive load switching and diode recovery times**



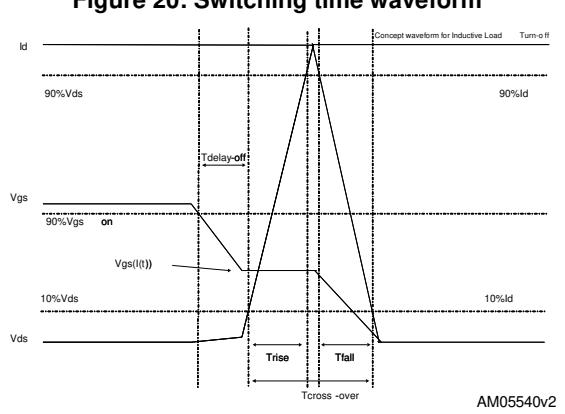
**Figure 18: Unclamped inductive load test circuit**



**Figure 19: Unclamped inductive waveform**



**Figure 20: Switching time waveform**



## 4 Package information

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status are available at: [www.st.com](http://www.st.com).  
ECOPACK® is an ST trademark.

## 4.1 PowerFLAT™ 8x8 HV package information

Figure 21: PowerFLAT™ 8x8 HV drawing

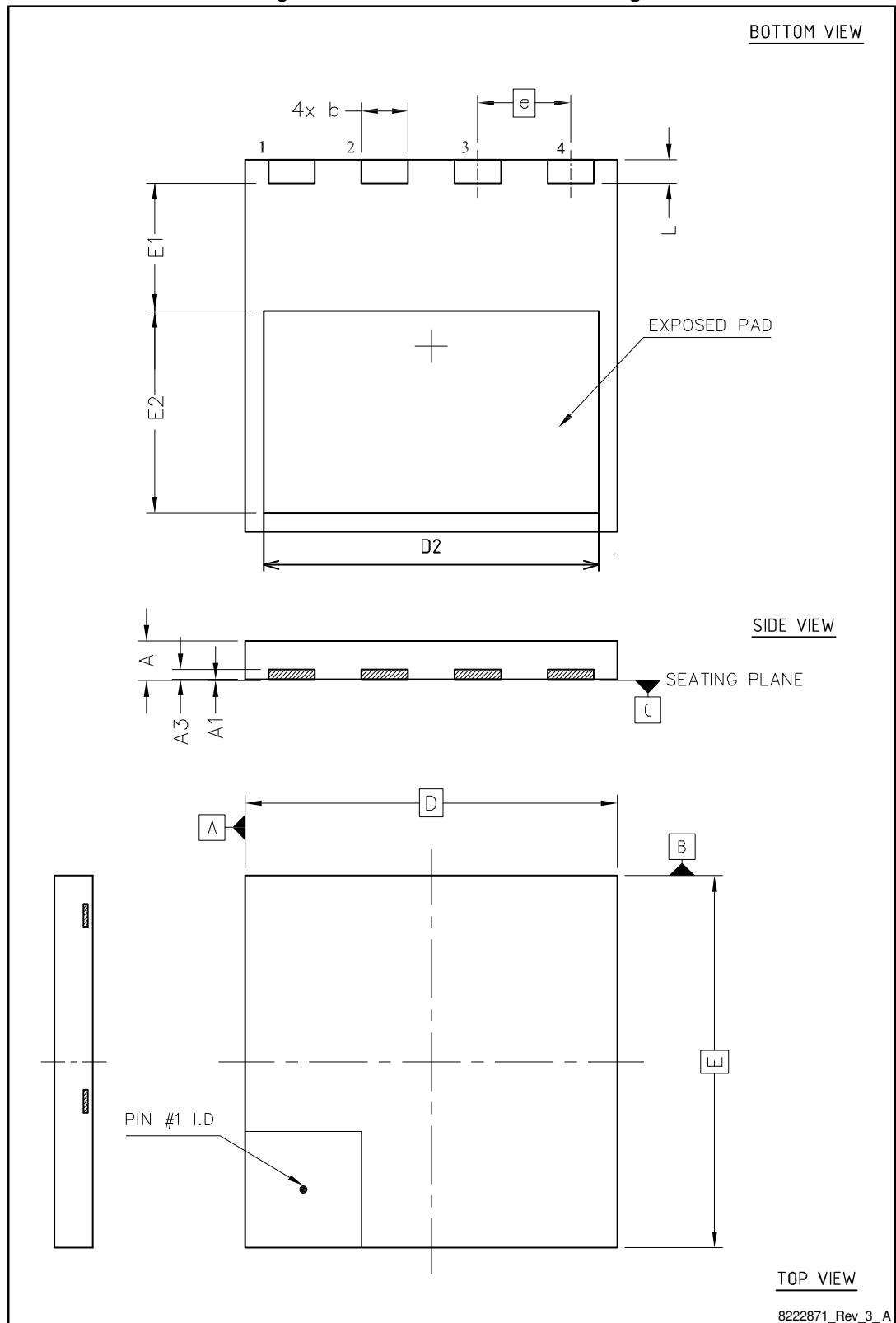
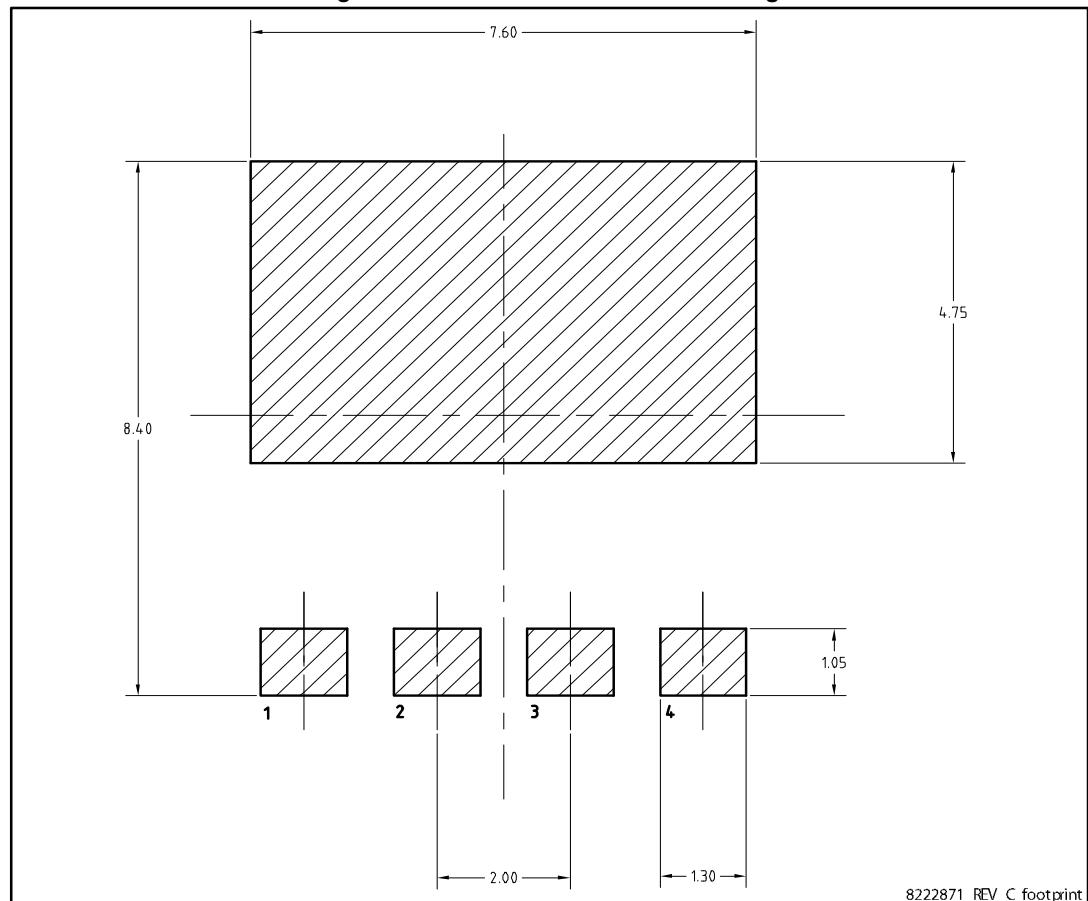


Table 8: PowerFLAT™ 8x8 HV mechanical data

Dim.	mm		
	Min.	Typ.	Max.
A	0.75	0.85	0.95
A1	0.00		0.05
A3	0.10	0.20	0.30
b	0.90	1.00	1.10
D	7.90	8.00	8.10
E	7.90	8.00	8.10
D2	7.10	7.20	7.30
E1	2.65	2.75	2.85
E2	4.25	4.35	4.45
e		2.00	
L	0.40	0.50	0.60

Figure 22: PowerFLAT™ 8x8 HV drawing



All the dimensions are in millimeters.

## 4.2 PowerFLAT™ 8x8 HV packing information

Figure 23: PowerFLAT™ 8x8 HV tape

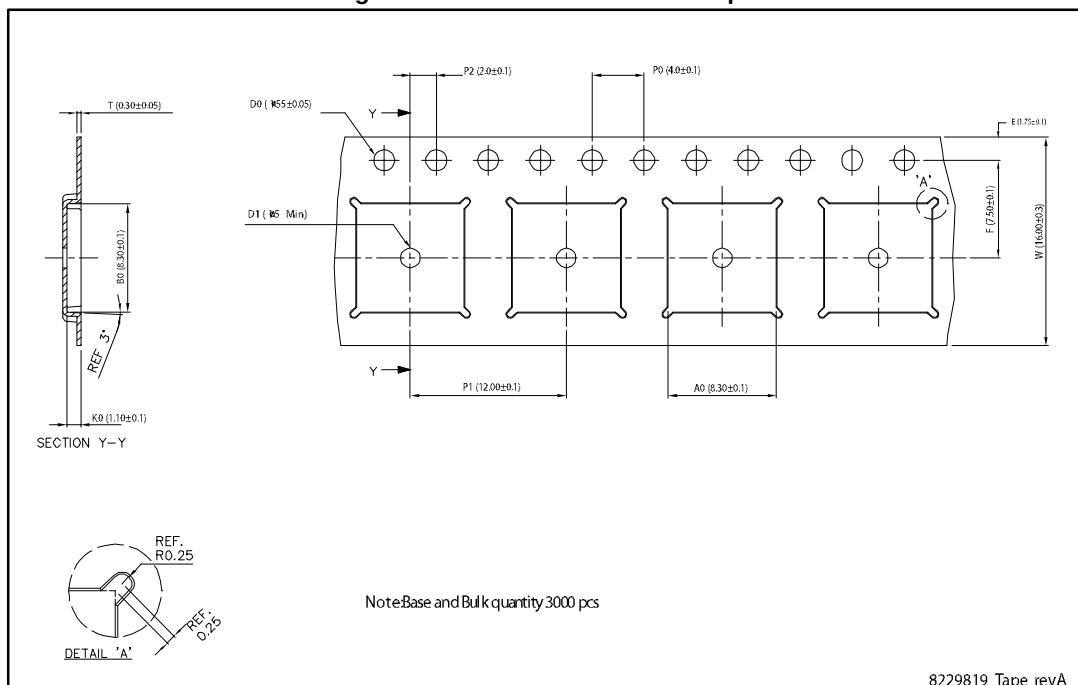


Figure 24: PowerFLAT™ 8x8 HV package orientation in carrier tape

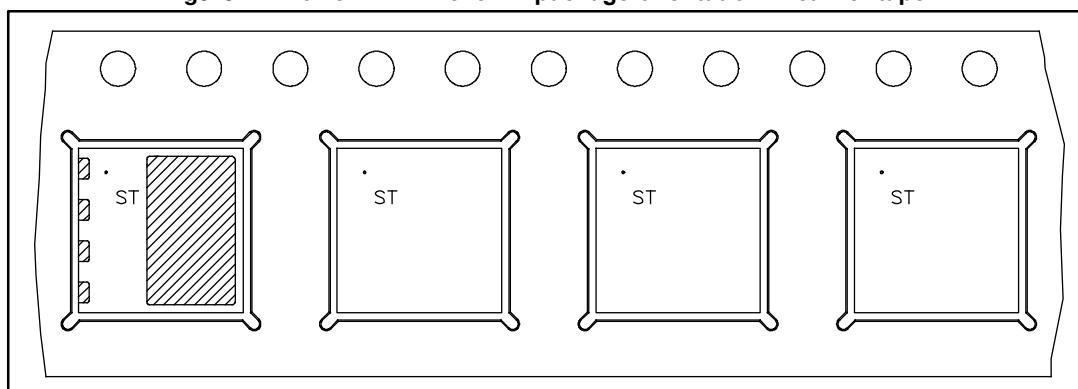
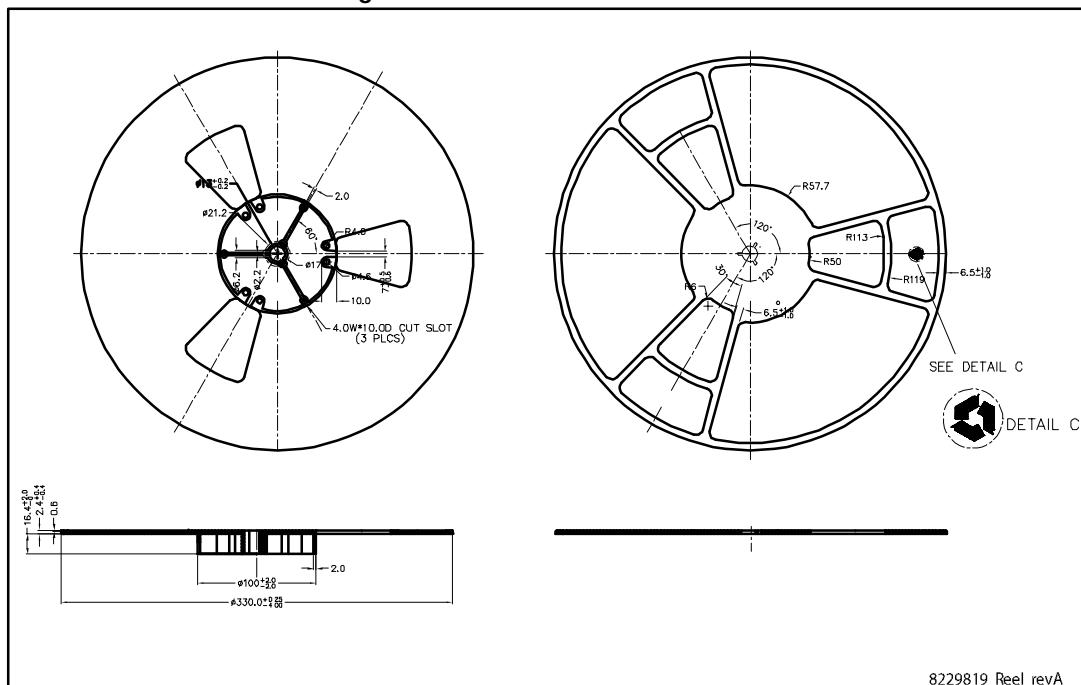


Figure 25: PowerFLAT™ 8x8 HV reel



## 5 Revision history

**Table 9: Document revision history**

Date	Revision	Changes
17-Jan-2013	1	First release.
27-Aug-2015	2	Updated title, features, internal schematic and description on cover page. Document status promoted from preliminary to production data. Updated package information. Minor text changes.

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